

Application/Control No.	
10/628 500	

Applicant(s)/Patent under Reexamination MIYAZAWA ET AL. Art Unit

Khiem D. Nguyen

Examiner

2823	

SEARCHED				
Class	Subclass	Date	Examiner	
438	379	11/22/2006	K.N.	
438	171	11/22/2006	K.N.	
438	190	11/22/2006	K.N.	
438	210	11/22/2006	K.N.	
438	238	11/22/2006	K.N.	
438	239	11/22/2006	K.N.	
438	381	11/22/2006	K.N.	
361	56	11/22/2006	K.N.	
361	277	11/22/2006	K.N.	
361	58	11/22/2006	K.N.	
361	271	11/22/2006	K.N.	
257	312	11/22/2006	K.N.	
257	595	11/22/2006	K.N.	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	 			
search (US	terference S-PGPUB), ch history.	11/22/2006	K.N.	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST text search updated (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB), see attached search history.	11/16/2006	K.N.		
Consulted Primary Examiner (Mr. Jackson Stephen W., AU 2836).	11/22/2006	K.N.		